

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/701,701	AERT ET AL.	
Examiner	Art Unit	
Pamala P. Sahwartz	1774	

SEARCHED					
Class	Subclass	Date	Examiner		
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Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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EPAB, JPAB, DN	PI	PB
USPT PGPB	7/21/	
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